

**Search Notes**

Application/Control No.

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Examiner

Leon J. Harper

Applicant(s)/Patent under  
Reexamination

BONILLA ET AL.

Art Unit

2166

**SEARCHED**

Class	Subclass	Date	Examiner
707	104.1,1,10 0,10,1,5	9/7/2006	LJH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR